<u> 2) INTERNATIONAL, APPLICATION PUBLI</u>SHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property Organization

International Bureau



13260 ENGLIGH IN STEINE FERNE SENER BENT BEIN 1810 EN 1810 BENT HER STEINE HAN BENT HER HER HER HER HER HER

(43) International Publication Date 31 December 2003 (31.12.2003)

PCT

(10) International Publication Number WO 2004/001730 A1

(51) International Patent Classification⁷:

G11B 7/125

(21) International Application Number:

PCT/IB2003/002394

(22) International Filing Date:

20 June 2003 (20.06.2003)

(25) Filing Language:

English

(26) Publication Language:

English

(30) Priority Data:

02077527.6

20 June 2002 (20.06.2002)

- (71) Applicant (for all designated States except US): KONIN-KLIJKE PHILIPS ELECTRONICS N.V. [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).
- (72) Inventor; and
- (75) Inventor/Applicant (for US only): LANGEREIS, Gerardus, R. [NL/NL]; c/o Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).
- (74) Agent: DEGUELLE, Wilhelmus, H., G.; Philips Intellectual Property & Standards, Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).
- (81) Designated States (national): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW,

MX, MZ, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.

(84) Designated States (regional): ARIPO patent (GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Declaration under Rule 4.17:

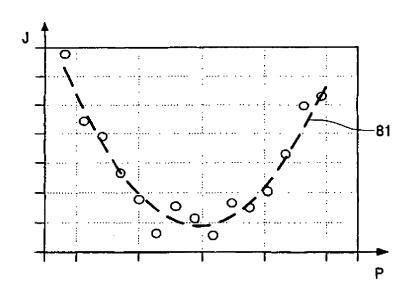
as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG, UZ, VC, VN, YU, ZA, ZM, ZW, ARIPO patent (GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG)

Published:

with international search report

[Continued on next page]

(54) Title: METHOD AND DEVICE FOR DETERMINING A SET OF RECORDING PULSE SERIES PARAMETERS FOR OPTICAL CARRIER RECORDING AND OPTICAL RECORD CARRIER



(57) Abstract: A method is described for determining a set of recording pulse series parameters for recording information on an optical record carrier. First a series of test patterns is written on the record carrier with a values of the parameters. On reading the test patterns, the jitter values of each read signal is determined. The optimum values of the parameters are derived from a linear dependence between the set of recording pulse series parameters and the relative jitter values. The invention relates also to a device arranged to perform the method. The invention further relates to an optical record carrier comprising the optimum recording power as determined by the method according to the invention.

 before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.

10

15

20

25

Method and device for determining a set of recording pulse series parameters for optical carrier recording and optical record carrier

The invention relates to a method of determining values of a set of recording pulse series parameters for optical carrier recording, where the recording pulse series are applied to a recording surface of an optical record carrier for writing a pattern of optically readable marks on the record carrier, a mark being formed by one recording pulse series, said method comprising writing a write test, each write test comprising a number N of test patterns, and each test pattern with pre-determined values of the set of the recording pulse series parameters, said values being different for each test pattern; and reading the test pattern and forming a read signal; and measuring jitter values of the read signal corresponding to each test pattern.

The invention also relates to a device for determining values of a set of recording pulse series parameters for optical carrier recording, comprising recording means for writing a pattern of optically readable marks on a record carrier by irradiating a recording surface of the record carrier with recording pulse series, a mark being formed by one recording pulse series; a test signal generator for generating a test signal comprising a test pattern and supplying the test signal to an input of the recording means; reading means for reading marks on the record carrier and supplying the read signal; a jitter detector for measuring jitter values of the read signal corresponding to the test pattern and supplying the jitter signal to control means; control means for optimizing the values of the set of the recording pulse series parameters and supplying a control signal representing the optimized set of the recording pulse series parameters; processing means for converting input information to be recorded into an output signal supplied to the recording means, the output signal corresponding to pulse series of radiation and representing the input information, where optimized values of the set of the recording pulse series parameters are provided by the control signal.

The invention further relates to an optical record carrier inscribable by a radiation beam, comprising a substrate and means on the substrate comprising control information.

WO 2004/001730 PCT/IB2003/002394

2

Japanese patent application No 11005244 discloses such a method for writing optical record carriers with optimized recording pulse parameters. According to the known method, a write test with standard values of write pulse parameters is performed. Subsequently, write tests are evaluated by evaluation parameters (e.g. jitter) and properties of an approximation formula for evaluation parameters are determined. Finally, the optimized values of recording pulse parameters are calculated using the approximation formula. The known method, however, requires complicated calculations for each specific set of standard values of write tests and employs the approximation formula which is not scalable and universal.

10

15

20

25

30

5

It is an object of the invention to provide a universal method and device for determining values of recording pulse parameters for optical carrier recording. It is also an object of the invention to provide a device being operative to perform such a method. It is further object of the invention to provide the optical record carrier, on which the information regarding the method is stored.

The first object is achieved when the method as described in the preamble is characterized in that the values of the set of the recording pulse series parameters are optimized using a linear dependence between the values of a set of recording pulse series parameters and relative jitter values. Another feature of the invention is that the minimum number N_{min} of the test patterns is dependent upon a number P of the recording pulse series parameters by the equation $N_{min} = 2*P+1$. The pattern of optically readable marks may correspond, for example, to a run-length limited code sequence. Furthermore, the set of the optimized values of the recording pulse series parameters may be recorded on the optical record carrier. The invention in its embodiment is characterized in that the test patterns comprise a random run-length limited code sequence. In another embodiment the parameter denotes a radiation power of one of the recording pulses of the recording pulse series or a width of one of the recording pulses of the recording pulse series. In the preferred embodiment the parameters for 3T marks differ from the parameters for longer marks and where T represents the time length of one period of a reference clock in a data signal.

The second object of the invention is achieved when the device as described in the preamble is characterized in that the control means is arranged to derive the optimized values of the set of the recording pulse series parameters using a linear dependence between the values of a set of recording pulse series parameters and relative jitter values. Furthermore, the device may comprise storage means for storing coefficients of the linear dependence between the values of a set of recording pulse series parameters and the relative jitter values. Storage means may also be operative to store the set of the optimized values of the set of the recording pulse series parameters.

The third object of the invention is achieved when the optical record carrier as described in the preamble is characterized in that the control information includes predetermined values of coefficients of a linear dependence between values of a set of recording pulse series parameters and relative jitter values. Furthermore, the control information may include optimized values of a set of recording pulse series parameters.

10

15

20

25

30

5

The objects, features and advantages of the invention will be apparent from the following, more specific description of embodiments of the invention as illustrated in accompanying drawings; therein:

Fig. 1 shows a diagram of an optical recording device according to the invention.

Fig. 2 shows jitter values in dependence with the recording power level (the recording pulse parameter) of the laser irradiation fitted with a non-linear curve.

Fig. 3 shows an optical record carrier according to invention.

Fig. 4 shown a strongly enlarged portion of the track comprising a pattern of marks in which the control information is encoded.

Fig. 1 shows a device and an optical recording record carrier 1 according to the invention. The disk-shaped record carrier 1 has a transparent substrate 3 and a recording layer 5 arranged on it. The recording layer 5 comprises a material suitable for writing information by means of a radiation beam. The recording material may be phase-change, dye or any other material suitable for optical recording. Information may be recorded on the

The device comprises a radiation source, e.g. a semiconductor laser 11, for emitting a radiation beam. A mark is formed when the recording layer 5 of the recording record carrier 1 is exposed to a single recording pulse of the radiation, characterized by a recording pulse parameter, which in this embodiment is a recording power level. A mark may also be written by a series of radiation pulses of equal or different lengths and one or more

recording power levels. The radiation beam is converged on the recording layer 5 via a beam

record carrier 1 in the form of optically detectable marks and lands on the record carrier.

WO 2004/001730 PCT/IB2003/002394

4

0

splitter 13, an objective lens 15 and the substrate 3. The record carrier 1 may also be air-incident, where the radiation beam is directly converged on the recording layer 5 without passing through the substrate 3. The semiconductor laser 11, the beam splitter 13 and the objective lens 15 form together a recording unit 17.

The device comprises also a processing unit 21, which consists of, for example, a processor of the processing unit 23, where the processor is understood to mean any means suitable for performing calculations, e.g. a microprocessor or a digital signal processor. A signal S (e.g. an information signal or a test signal), representing the information to be written on the record carrier 1, is fed into the processor of the processing unit 21. The processing unit 21 determines the set of the recording pulse series parameters for recording the information on the record carrier 1. In the specific embodiment the set of the recording pulse series parameters consists of recording power levels of the recording pulse. Determination of the recording power levels is performed taking into account an optimum recording power levels P_{opt} calculated by a control unit 61. The control signal S_C of the control unit 61 is supplied to the processing unit 21. Once the optimum recording power levels P_{opt} for a specific record carrier 1 is calculated, it may be supplied to the processing unit 21 from the information recorded on the record carrier 1. An output of the processing unit 21 is connected with the semiconductor laser 11 and the control unit 61.

The device further comprises a test signal generator 31. The test signal generator 31 may consist of a processor of the test signal generator, which is suitable of generating the test signal S_T . The test signal S_T should preferably represent a test pattern which, when coded in the so-called eighth-to-fourteen modulation (EFM), comprises marks of all length. The test signal S_T may be a random signal. The test signal S_T is supplied to the input of the processing unit 21.

The device further comprises a reading unit 41 formed by the semiconductor laser 11, the beam splitter 13, the objective lens 15, a detection system 43 and a circuit (not shown on the diagram) of the reading unit. The recorded record carrier 1 is exposed to the radiation beam at the reading power level P_{read} emitted from the semiconductor laser 11. Radiation reflected from the record carrier 1 is converged by the objective lens 15 and, after passing through the beam splitter 13, falls on the detection system 43, which converts the incident radiation into electric detector signals. The detector signals are input to a circuit of the reading unit, which derives several signals from the detector signals, such as a read signal S_R representing the information being read from the record carrier 1. The read signal S_R is further fed into a jitter detector 51. The jitter detector 51 measures jitter values of the read

5

10

15

20

25

30

10

15

20

25

30

signal S_R . Jitter is defined as the variance of a certain timing error. This can be either data to clock or data to data timing errors. From that point of view it is understood easily that data to data jitter is $\sqrt{2}$ -times larger than data to clock jitter since data to data jitter is the result of two not correlated jittering data to clock edges. In spite of this difference, all types of jitters can be treated similar in the coming arguments.

The jitter values are supplied into the control unit 61 comprising a processor of the control unit, which may be a simple microprocessor. The control unit 61 is also supplied with the signal S_P from the processing unit 61 containing the values the recording power levels P with which the test patterns have been recorded. The role of the control unit 61 is to derive optimum values of the recording power levels P_{opt} for the record carrier 1 and supply a control signal S_C to the processing unit 21.

Before recording information on record carrier, the device sets its recording power levels P to the optimum values by performing the following procedure. First, a series of test patterns are recorded on the record carrier 1, each with a different pre-determined recording power level P.

The range of pre-determined powers may be selected on the basis of an indicative power level derived from control information on the record carrier 1. Subsequent patterns may be written with a step-wise increased power. The patterns may be written anywhere on the record carrier 1, also in specially provide test areas.

After reading the test patterns from the record carrier 1, the processor of the control unit 61 forms a series of value pairs for the jitter J of the read signal S_R for each pattern, provided by the jitter detector 51, and the pre-determined recording power levels with which that pattern has been recorded - provided by the processing unit 21.

Fig. 2 shows a series of N=15 points, each representing a pair of values of jitter J and pre-determined recording power level of a test pattern. The points form a dependence 81 of jitter J values with respect to the pre-determined recording power level. It is apparent from fig. 2 that the dependence exhibits a non-linear (bathtub) characteristics.

Optimization of the recording pulse parameters is based on the following. A parameter x in a certain recording pulse parameter (the parameter in a write strategy) which can be either an amplitude during a clock subdivision or a location of an edge in time. Consider the range $x \pm \delta x$ in which this parameter results linearly into a shift in a specific edge in the hf-signal. In general, thermally balanced write strategies are defined in such a way that parameter x affects a specific edge between runlengths. For data to clock jitter measured on random EFM, jitter as a function of the parameter x, can be written as:

$$J(x) = J_{hottom} + a_x (x - \hat{x})^2 \tag{1}$$

with:

10

15

20

J_{Bottom} - bottom jitter. .

5 a_x - the sensitivity of the jitter on variations.

A thermally balanced write strategy is described in the International patent application PCT/EP01/04566. Thermal crosstalk parameters further described in the embodiment will be the parameters defined in this application. The parameters for 3T marks (lands) (c, u) differ from the parameters for longer marks (d and v). The parameters c and d denote intermediate power level and the parameters u and v denote the elevated power level of the recording pulse.

A parabola is defined by three measurement points. So, if we measure the jitter for at least three settings of a certain parameter x, we are able to calculate the best setting \hat{x} for a single parameter resulting into the lowest jitter.

Equation 1 is valid in a linearized region for a single write strategy parameter. Consider, in addition, the assumption that the jitter variations due to all the write strategy parameters are not correlated. The practical impact of this assumption is that the optimum setting of a parameter with respect to jitter is not dependent on the settings of the other parameters. The idea is to solve the vector $\hat{\mathbf{x}}$ from a number of $J(\mathbf{x})$ measurements. Note that if the $\hat{\mathbf{x}}$ -vector has size P (which means that the write strategy has P parameters), the smallest number of measurements equals N = 2P + 1. Under this assumption, we arrive at:

$$J_{n} = J_{bottom} + \sum_{p} a_{p} (x_{n,p} - \hat{x}_{p})^{2}$$
 (2)

with

p = 0..P-125 the number of write strategy parameters; a vector with the values of the P write strategy parameters; x â a vector with the optimum parameters to be determined; a vector with the sensitivities of each parameter; a lowest achievable jitter when $x = \hat{x}$ and J_{Bottom} the measured jitter for parameters x. 30 $J(\mathbf{x})$ n = 0..N-1the number of the measurement.

Equation 2 can be put into a matrix notation from which we can see that the vector of interest $\hat{\mathbf{x}}$ is now implicitly defined. However, the bottom jitter J_{Bottom} is not of interest at first instance and can be eliminated by subtracting measurements J_0 to J_{N-2} with J_{N-1} .

The advantage of this operation is that equation (4.5) is now linear with the optimum parameter vector $\hat{\mathbf{x}}$ which can be seen from the matrix notation:

$$\Delta J = \Delta X \cdot ax$$

10 with

5

15

20

25

30

$$\Delta x = \begin{bmatrix} x_{0,0}^2 - x_{N-1,0}^2 & -2(x_{0,0} - x_{N-1,0}) & \cdots & x_{0,P-1}^2 - x_{N-1,P-1}^2 & -2(x_{0,P-1} - x_{N-1,P-1}) \\ \vdots & \vdots & \ddots & \vdots & \vdots \\ x_{N-2,0}^2 - x_{N-1,0}^2 & -2(x_{N-2,0} - x_{N-1,0}) & \cdots & x_{N-2,P-1}^2 - x_{N-1,P-1}^2 & -2(x_{N-2,P-1} - x_{N-1,P-1}) \end{bmatrix}$$

$$\Delta J = \begin{bmatrix} \Delta J_0 \\ \vdots \\ \Delta J_{N-2} \end{bmatrix} \quad \text{and} \quad ax = \begin{bmatrix} a_0 \\ a_0 \hat{x}_0 \\ \vdots \\ a_{P-1} \\ a_{P-1} \hat{x}_{P-1} \end{bmatrix}$$
(3)

Each vector or matrix has its own information. The differential measurement vector $\Delta \mathbf{J}$ has length N-1 (N the number of measurements) and is therefore known. The differential input vector $\Delta \mathbf{X}$ is applied to the system by the operator, and therefore also known. Since, in general $\Delta \mathbf{X}$ is not square (so has no inverse $\Delta \mathbf{X}^{-1}$) and the linear minimum mean square parameter estimation algorithm, the vector to be determined is the sensitivity and optimum parameter vector $\mathbf{a}\mathbf{x}$ which can be found using

$$ax = (\Delta X^T \Delta X)^{-1} \Delta X^T \Delta J \tag{4}$$

Equation 4 can also be used for N > 2P+1. From the result vector \mathbf{ax} , the sensitivities can be found at the even entries, while the optimum parameters can then be found after normalizing the odd entries to these sensitivities. The relative values of the sensitivities will be determined by: a number of factors (e.g. the frequency of occurrence of the corresponding runlength in the EFM sequence, the width in time modulated by this parameter in the strategy, the write power change in case of an amplitude parameter is equal to the parameter value times the timeslot in which it is effective. The parameters c and d in the TBWS last for only T/4, while u and v are 9T/4 long, this will affect \mathbf{ac} , \mathbf{ad} , \mathbf{au} and \mathbf{av} , etc.).

10

20

25

30

In the specific embodiment using the Thermally Balanced Write Strategy (TBWS) with thermal crosstalk compensation parameters

c for land I3,

d for land 14,

u for pit I3 and

v for pit 14,

a series of parameter variation measurements are carried out. The disc is a Mitsui (internal reference number CDR01-001) phthalo disc which has its optimum write power for 16X at 25 mW (main spot on disc). The automatic iterative optimizer gives

		Merit:	RMS-norm	max-norm
	•	С	0.722	0.542
		đ	1.000	0.959
	-	u	1.110	1.096
15		v	1.023	1.037
		Leading Jitter	7.0 %	6.1 %
		Trailing Jitter	6.4%	6.3%

after 30 iterations, with all parameters represented as multiplication factors for the write power.

First, only the land effects are optimized (number of parameters P=2). Parameter c is changed in three steps: 0.25, 0.50 and 0.75, at each c-value, d is changed in three steps: 0.5, 0.75 and 1.00. These ranges are chosen because: from the implementation of TBWS we know that the compensation for c has to be stronger than for d. Both c and d should be lower than 1. Five measurements are sufficient for this P=2 situation, but nine will give a more reliable fit. The u and v parameters are chosen 1.10 and 1.04 respectively, because these are the values that are general to almost all the discs observed in the ROS-DOS-TOS measurement sequence. Jitters are read out at 2X.

The fit algorithm is applied offline using a MathCad 6.0 worksheet. The found optimum parameters are:

c = 0.496 with sensitivity 8.6 and

d = 0.842 with sensitivity 5.2.

The difference between the sensitivities can be ascribed to the ratio 3T/4T because these are affected by the c and d parameters respectively. After the parameters are

10

15

found, the expected (lowest achievable) value of J_{Bottom} can be calculated using equation 2 and is equal to 6.8%.

When expanding the measurement data of the previous subsection (for c = 0.25, 0.50, 0.75 and d = 0.50, 0.75, 1.00) with measurements for u = 1.05, 1.10, 1,15 and v = 1.00, 1.05 and 1.10, the four thermal crosstalk compensation parameters in the TBWS can be fitted at the same time. In the additional measurements u and v are changed, v and v are set to 0.65 and 0.85 respectively because these are the most general settings. Note that v and v are the parameters, note that v and v are the measurement with v and v are the measurement wit

Algorithm returns

c = 0.464 with sensitivity 9.2,

d = 0.792 with sensitivity 5.1,

u = 1.105 with sensitivity 1249,

v = 1.039 with sensitivity 300,

a bottom jitter of 6.9.

The ratio between the sensitivities for c,d and u,v are the result of the width of the u and v levels which are 9/4 times larger than the c and d levels.

In another embodiment: the ΔT after a 3T land and the ΔT after a 4T land are changed in four steps. The recorded jitters (in %) are in the next table. The values for ΔP :

Jitter in %		ΔT after 4T land			
		3T/16	T/8	T/16	OT
ΔT after	3T/16	8.37	7.40	7.17	7.84
3T land	T/8	8.64	7.29	6.61	6.94
	T/16	9.80	8.28	7.48	7.37
	OT	11.49	10.03	9.10	8.78

The fitted results, together with the measured data:

ΔT after 3T: Optimum setting 0.126T, sensitivity 8.6

25 ΔT after 4T: Optimum setting 0.040T, sensitivity 5.3

With this example, the perfect parabolic nature of the jitter dependency on thermal balancing parameters is confirmed for DVD+R. Therefore, the complete optimization algorithm can be applied for the write once DVD platform.

10

15

20

Ĭ.

Fig. 3 shows a disc-shaped optical record carrier 1 according to the invention. Recording layer of the record carrier can be inscribed optically or magneto-optically by a recording device. Information on the record carrier is represented by pattern of marks. Information is recorded in track by a recording process in which each mark is formed by one or more recording pulses of constant or varying recording power levels P. The recording parameters of the recording process, such as the recording power level P, the number of pulses are to be tuned for the record carrier, in particular due to its material properties. An example of an inscribable record carrier is the known CD Write-Once. The record carrier has a continuous track 101 intended for recording. The track 101 may be spiral and in the form of an embossed groove or ridge. The area of the record carrier is divided in an information recording area 103 for recording user information and control area 105 for storing information relevant for recording user information. The control area 105 is marked by a dashed track in the fig.. The value of optimum recording power levels Popt for recording the record carrier may be stored as a pattern of control information in the control area 105. When the control area is embossed, the manufacturer of the record carrier 1 must record the value. Alternatively, the value may be recorded by user during, for instance, initialization of the record carrier 1, allowing the recording of a carrier-specific value.

Fig. 4 shown a strongly enlarged portion 107 of the track comprising a pattern of marks 109 in which the control information is encoded.

Although has been explained by an embodiment using the recording power level as recording parameter, it will be clear that other recording parameters (e.g. specific timing of the recording pulse pattern for recording a mark) may be employed in the invention.

It is apparent to those skilled in the art that the invention may be applied to alternative optical recording systems such as e.g. DVD, Blue-Ray, etc.

CLAIMS:

5

20

- 1. A method of determining values of a set of recording pulse series parameters for optical carrier recording, where the recording pulse series are applied to a recording surface of an optical record carrier for writing a pattern of optically readable marks on the record carrier, a mark being formed by one recording pulse series, said method comprising:
- writing a write test, each write test comprising a number N of test patterns, and each test pattern with pre-determined values of the set of the recording pulse series parameters, said values being different for each test pattern; and
 - reading the test pattern and forming a read signal; and
- measuring jitter values of the read signal corresponding to each test pattern,
 where the values of the set of the recording pulse series parameters are optimized using a linear dependence between the values of a set of recording pulse series parameters and relative jitter values.
- A method of claim 1, where the minimum number N_{min} of the test patterns is
 dependent upon a number P of the recording pulse series parameters by the equation:
 N_{min} = 2*P+1.
 - 3. A method of claim 1, where the pattern of optically readable marks corresponds to a run-length limited code sequence.

4. A method of claim 1, where the test patterns comprise a random run-length limited code sequence.

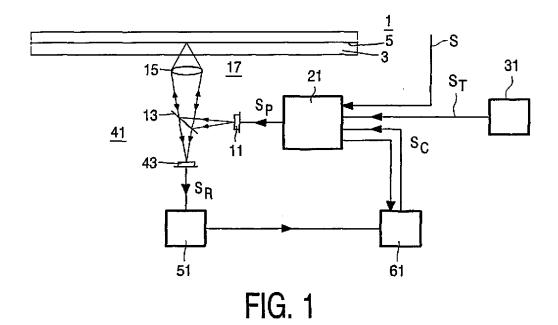
- 5. A method of claim 1, where the parameter denotes a radiation power of one of the recording pulses of the recording pulse series.
 - 6. A method of claim 1, where the parameter denotes a width of one of the recording pulses of the recording pulse series.

- 7. A method of claim 1, where the set of the optimized values of the recording pulse series parameters is recorded on the optical record carrier.
- 8. A method of claim 5 or 6, where the parameters for 3T marks differ from the parameters for longer marks and where T represents the time length of one period of a reference clock in a data signal.
 - 9. A device for determining values of a set of recording pulse series parameters for optical carrier recording, comprising:
- recording means for writing a pattern of optically readable marks on a record carrier by irradiating a recording surface of the record carrier with recording pulse series, a mark being formed by one recording pulse series;
 - a test signal generator for generating a test signal comprising a test pattern and supplying the test signal to an input of the recording means;
- reading means for reading marks on the record carrier and supplying the read signal;
 - a jitter detector for measuring jitter values of the read signal corresponding to the test pattern and supplying the jitter signal to control means;
 - control means for optimizing the values of the set of the recording pulse series parameters and supplying a control signal representing the optimized set of the recording pulse series parameters;
 - processing means for converting input information to be recorded into an output signal supplied to the recording means, the output signal corresponding to pulse series of radiation and representing the input information, where optimized values of the set of the recording pulse series parameters are provided by the control signal, where the control means is arranged to derive the optimized values of the set of the recording pulse series parameters using a linear dependence between the values of a set of recording pulse series parameters and relative jitter values.
- 30 10. A device of claim 9, comprising storage means for storing coefficients of the linear dependence between the values of a set of recording pulse series parameters and the relative jitter values.

20

25

- 11. A device of claim 10 or claim 11, comprising storage means for storing the set of the optimized values of the set of the recording pulse series parameters.
- 12. An optical record carrier inscribable by a radiation beam, comprising a substrate and means on the substrate comprising control information, where the control information includes pre-determined values of coefficients of a linear dependence between values of a set of recording pulse series parameters and relative jitter values.
- 13. An optical record carrier of claim 12, where the control information includes optimized values of a set of recording pulse series parameters.



81 0 0 0 0

FIG. 2

WO 2004/001730 PCT/IB2003/002394

2/2

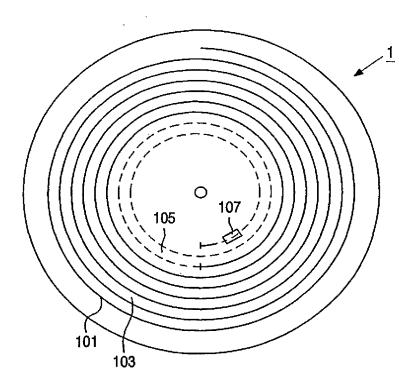


FIG. 3

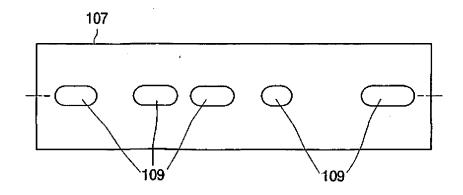


FIG. 4

In :jonal Application No PCT/IB 03/02394

4 01 4000	FIGURE OF SUBJECT LITTERS					
IPC 7	FICATION OF SUBJECT MATTER G11B7/125	•				
	International Patent Classification (IPC) or to both national classification	ation and IPC				
	SEARCHED cumentation searched (classification system totlowed by classification	on symbole)				
IPC 7	G11B	on symbols,				
Documentat	ion searched other than minimum documentation to the extent that s	such documents are included in the fields sea	rched			
	•					
F(, ')						
l	ata base consulted during the international search (name of data ba	se and, where practical, search terms used)				
EPO-lini	ternal, PAJ, WPI Data					
			•			
C. DOCUM	ENTS CONSIDERED TO BE RELEVANT					
Category *	Citation of document, with indication, where appropriate, of the rel	evant passages	Relevant to claim No.			
			<u></u>			
Х	EP 0 865 035 A (HITACHI LTD)		1,9			
	16 September 1998 (1998-09-16)					
	column 7 -column 14					
x	WO 99 30316 A (KONINKL PHILIPS EL	ECTRONICS	1,9,12			
^	NV ; PHILIPS SVENSKA AB (SE))		-,0,12			
	17 June 1999 (1999-06-17)					
	page 10					
Α	WO 02 47072 A (KONINKL PHILIPS EL	FCTRONTCS	1-13			
	NV) 13 June 2002 (2002-06-13)	ELOTRONICO	^ 13			
	the whole document					
٨			1 10			
A	US 5 793 737 A (DEN BOEF ARIE J) 11 August 1998 (1998-08-11)	1	1-13			
	the whole document	İ				
	-	-/				
	<u> </u>					
χ Furt	her documents are listed in the continuation of box C.	Patent family members are listed in	annex.			
° Special ca	legories of cited documents :	"T" later document published after the intern	national filing date			
	ent defining the general state of the art which is not	or priority date and not in conflict with t cited to understand the principle or the	ne application but			
	lered to be of particular relevance document but published on or after the International	invention				
filing d	filing date "X" document of particular relevance; the claimed invention cannot be considered novel or carnot be considered to "L" gocument which may throw doubts on priority claim(s) or "L" gocument which may throw doubts on priority claim(s) or					
which	is cited to establish the publication date of another n or other special reason (as specified)	"Y" document of particular relevance; the cla	aimed invention			
O docume	ent referring to an oral disclosure, use, exhibition or means	cannot be considered to Involve an invi document is combined with one or mor ments, such combination being obvious	e other such docu-			
*P" docume	ent published prior to the international filing date but	in the art.	•			
later than the priority date claimed "8" document member of the same patent family						
Date of the	actual completion of the international search	Date of mailing of the international sear	cn report			
8	October 2003	17/10/2003				
Name and r	mailing address of the ISA European Patent Office, P.B. 5818 Patentiaan 2	Authorized officer				
	NL – 2280 HV Rijswljk Tel. (+31–70) 340–2040, Tx. 31 651 epo ni,	Damp C				
!	Fax: (+31-70) 340-3016					

Form PCT/ISA/210 (second sheet) (July 1992)

Int ional Application No PCT/IB 03/02394

Alian) DOCUMENTS CONCIDEDED TO BE DELEVANT	PCI/IB 03/02394
	Relevant to daim No.
EP 0 762 399 A (RICOH KK) 12 March 1997 (1997-03-12) the whole document	1-13
WO 02 41306 A (KONINKL PHILIPS ELECTRONICS NV) 23 May 2002 (2002-05-23) the whole document	1-13
US 5 732 061 A (IDE HIROSHI ET AL) 24 March 1998 (1998-03-24) the whole document	1-13
	:
J.	
	·
	12 March 1997 (1997-03-12) the whole document WO 02 41306 A (KONINKL PHILIPS ELECTRONICS NV) 23 May 2002 (2002-05-23) the whole document US 5 732 061 A (IDE HIROSHI ET AL) 24 March 1998 (1998-03-24) the whole document

Information on patent family members

In:ional Application No PCT/IB 03/02394

				1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	03/02394
Patent document cited in search report		Publication date		Patent family member(s)	Publication date
EP 0865035	A	16-09-1998	EΡ	1033704 A1	06-09-2000
			£Ρ	0865035 A2	16-09-1998
			ĴΡ	10320777 A	04-12-1998
			T₩	382703 B	21-02-2000
			ÜŜ	6269062 B1	31-07-2001
			บร	2002085463 A1	04-07-2002
			US	2001043529 A1	22-11-2001
				Z0010435Z9 M1	22-11-2001
WO 9930316	Α	17-06-1999	AU	1171199 A	28-06-1999
			BR	9807557 A	28-03-2000
			CN	1117358 B	06-08-2003
			EP	0958575 A1	24-11-1999
			HU	0003818 A2	28-02-2001
			WO	9930316 A2	17-06-1999
			JP	2001511289 T	07-08-2001
		•	TR	9901868 T1	21-02-2000
			ŤŴ	430790 B	21-04-2001
			Ų\$	6243339 B1	05-06-2001
				0243339 BI	
WO 0247072	Α	13-06-2002	ΑU	2794602 A	18-06-2002
			BR	0108071 A	29-10-2002
			CN	1397067 T	12-02-2003
			CZ	20022652 A3	13-11-2002
			ЙŌ	0247072 A1	13-06-2002
			ËP	1346350 A1	24-09-2003
			บิร	2002085462 A1	04-07-2002
US 5793737	Α	11-08-1998	MO	9825266 Al	11-06-1998
03 3/3/3/	n	11-00-1330	MO	9825267 A1	11-06-1998
	,	•		6134209 A	17-10-2000
			US		
			CN	1214789 A	21-04-1999
			CN	1214790 A	21-04-1999
			EP	0888614 A1	07-01-1999
			EΡ	0880778 A1	02-12-1998
			ΙL	125635 A	26-08-2001
			JP	2000504466 T	11-04-2000
			JP	2000504467 T	11-04-2000
			ΤW	446937 B	21-07-2001
			US	5978351 A	02-11-1999
			ZA	9710932 A	04-06-1999
EP 0762399	A	12-03-1997	JP	3124721 B2	15-01-2001
_, 0,01000	• • •	75 40 737/	ĴΡ	9138946 A	27-05-1997
			ĔΡ	0762399 A1	12-03-1997
			ĴΡ	2001060321 A	06-03-2001
			JP	2001000321 A 2002251732 A	06-09-2002
			US	5790505 A	04-08-1998
			_ -	<u> </u>	
110 00 11 000	A	23-05-2002	AU	2184902 A	27-05-2002
WO 0241306			BG	106913 A	31-03-2003
WU U241306			BR	0107658 A	19-11-2002
WO 0241306	-			つるひとつのひ まつ	23-05-2002
WO 0241306	**		CA	2406728 Al	
WO U241306			CA CN	1416566 T	07-05-2003
WO U241306	-				
WO U241306	-		CN	1416566 T	07-05-2003
WO UZ41306	-		CN CZ	1416566 T 20022449 A3	07-05-2003 13-11-2002
WO U241306	-		CN CZ WO	1416566 T 20022449 A3 0241306 A1	07-05-2003 13-11-2002 23-05-2002

Form PCT/ISA/210 (patent family annex) (July 1992)

Information on patent family members

PCT/IB 03/02394

Patent document cited in search report		Publication date		Patent family member(s)	Publication date
WO 0241306	Α		SK	10422002 A3	03-12-2002
			US	2002114235 A1	22-08-2002
US 5732061	Α	24-03-1998	JP	2915098 B2	05-07-1999
			JP	4061028 A	27-02-1992
			JР	2865841 B2	08-03-1999
			JP	4137224 A	12 ~05 ~19 92
			J۴	3063314 B2	12-07-2000
			JP	5135363 A	01-06-1993
			JP	5298737 A	12-11-1993
			JP	3036240 B2	24-04-2000
			JP	6036377 A	10-02-1994
			JP	6084173 A	25-03-1994
			US	5590111 A	31-12-1996
			U\$	5418770 A	23-05-1995
		+	US	5642343 A	24-06-1997
			US	5345434 A	06~09–1994
			US	5513165 A	30-04-1996
			DE	69124046 D1	20-02-1997
			EP	0477892 A2	01-04-1992
			DE	4293957 C2	26-02-1998
			DΕ	4293957 T0	31 - 07 -199 7
			MO	9310527 A1	27-05-1993
			JP	3345932 B2	18-11-2002
			JP	5290437 A	0 5- 11-19 9 3

Form PCT/ISA/210 (patent lamily annex) (July 1992)